

TEST REPORT

on behalf of

ZHEJIANG FENGJIN TECHNOLOGY CO., LTD.

Multi Banknote Discriminator (Counter), Banknote Detector

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GENERAL INFORMATION

Product Description for Equipment Under Test (EUT)

The product that is produced by **ZHEJIANG FENGJIN TECHNOLOGY CO., LTD.** test model: **2108**. the "EUT" as referred to in this report is a **Multi Banknote Discriminator (Counter), Banknote Detector**.

Complete test was conducted on Multi Banknote Discriminator (Counter), Banknote Detector.

Objective

In order to meet the EMC requirements approved by GENELEC, the following standards will be cited:

1. EN61000-3-2:2014, EMC-Limits-Limits for the harmonic current emissions (equipment input current up to and including 16 A per phase).
2. EN61000-3-3:2013 , EMC-Limits-Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16 A per phase and not subject to conditional connection.
3. N 55032:2015 Information technology equipment-Radio disturbance characteristics- Limits and methods of measurement.
4. EN 55035:2017 Information technology equipment-Immunity characteristics-Limits and methods of measurement.

The objective of the manufacturer is to demonstrate compliance with the limits for Information Technology Equipment -Limits and methods of measurement.

Note: The test data is only valid for the test sample. There is possible deviation from the original test data for other products

Equipment Modifications

No modification to the EUT was made by **Shanghai Global Testing Services Co., Ltd** to make sure the EUT comply with applicable limits.

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1.4 Test Data and Records

Test case does not apply to the test object(<75W)

1.5 Verdict

The EUT met the requirement.

2.4 Test Data and Records

Flicker	Limit	Value
Short-term flicker Indicator Pst	1.0	0.273
Long -term flicker Indicator Plt	0.65	0.128

Voltage fluctuation	Limit	Value
Relative voltage change characteristic(dt)	500ms	0
Max relative voltage change characteristic(dmax)	6%	0.235%

Result: PASSED

2.5 Verdict

The EUT met the requirement.

3 - EN55032

3.1 Conducted disturbance at the Mains Terminals.

3.1.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Due date
1	EMI test receiver	Rohde & Schwarz	ESCS25	1005426	2017-09-04	2018-09-03
2	Line impedance stabilization network	SCHWARZBECK	NSLK838	8127-350	2017-12-08	2018-12-07

3.1.2 Description of Measurement Conditions

Temperature: 21 °C

Humidity: 58%

Pressure: 1033mbar

Electromagnetic environment: normal

3.1.3 Limits for conducted disturbance at the mains terminal of class B ITE

Frequency range MHz	Limit values dB(μV)	
	Quasi-peak	Average
0.15 to 0.5	66~56	56~46
0.5 to 5	56	46
5 to 30	60	50

NOTE 1: The lower limit shall apply at the transition frequencies.
NOTE 2: The limit decreases linearly with the frequency in the range 0,15 MHz to 0,50 MHz.

3.2 Conducted disturbance at telecommunication ports

3.2.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Due date
1	EMI test receiver	Rohde & Schwarz	ESCS25	1005426	2017-12-04	2018-12-03
2	Line impedance stabilization network	SCHWARZBECK	NSLK838	8127-350	2017-12-08	2018-12-07

3.2.2 Description of Measurement Conditions

Temperature: 20°C

Humidity: 60%

Pressure: 1033mbar

Electromagnetic environment: normal

3.2.3 Limits for conducted disturbance at the mains terminal of class B ITE.

Frequency range MHz	Limit values dB(μ V)	
	Quasi-peak	Average
0.15 to 0.5	84~74	74~64
0.5 to 30	74	64

NOTE 1: The lower limit shall apply at the transition frequencies.
NOTE 2: The limit decreases linearly with the frequency in the range 0,15 MHz to 0,50 MHz.

3.2.4 Configuration

The configuration is in accordance with the requirement in EN55032

3.2.5 Test Data and Records

Test case does not apply to the test object

3.2.6 Verdict

The EUT met the requirement.

3.3 Radiation Disturbances

3.3.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date	Cal. Due date
1	EMI test receiver	Rohde & Schwarz	ESU40	100987	2017-12-03	2018-12-02
2	Antenna	SCHWARZBECK	VULB9168	9168-493	2017-12-03	2018-12-02
3	CONTROLLER	INNCO	CO200	722	/	/

3.3.2 Description of Measurement Conditions

Temperature: 20°C

Humidity: 60%

Pressure: 1033mbar

Electromagnetic environment: normal

3.3.3 Limits of radiated disturbances of class B ITE at a measuring distance of 3m.

Frequency range MHz	Quasi-peak limits(3m) dB(μV/m)
30 to 230	40
230 to 1000	47
NOTE: The lower limit shall apply at the transition frequency.	
NOTE: Additional provisions may be required for cases where interference occurs.	

3.3.4 Test procedure and the test set-up

Procedure

- The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3m semi/full-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- The antenna is a broadband antenna, and its height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarization of the antenna are set to make the measurement.
- For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters and the turn table was turned from 0 degrees to 360 degrees to find the maximum reading.
- The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- If the emission level of the EUT in peak mode was 10 dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10 dB margin would be retested one by one using the quasi- peak method or average method as specified and then reported In Data sheet peak mode and QP mode.

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4 –EN55035

Description of Performance Criterion (According with EN55035 Section 7.1)

Performance Criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user reasonably expects from the equipment if used as intended.

Performance Criterion B

After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance Criterion C

Loss of function is allowed, provided the function is self-recoverable, or restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Function and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost

4.1 SURGES

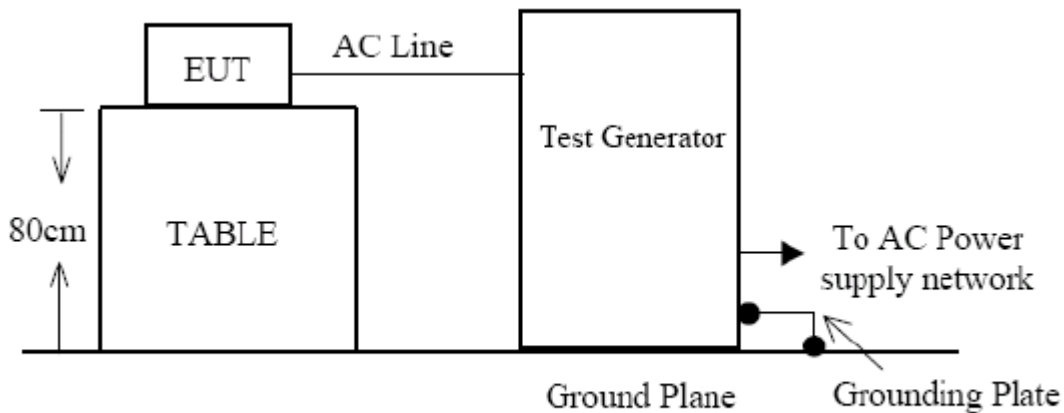
4.1.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Series No.	Cal. Date	Cal. date Due
1	Ultra-compact simulator	EM test	UCS500M4	V050710012 2	2017-10-08	2018-10-07

4.1.2 Description of Measurement Conditions

Temperature: 21 °C
 Humidity: 58%
 Pressure: 1033mbar
 Electromagnetic environment: normal

4.1.3 Configuration



Remark: Test generator includes control center, surge combination and coupler.

4.1.4 Test Data and Records

Level	Voltage	Poll	Phase angle	Path	Pass	Fail
1	1.0kV	±	0°, 90°, 180°, 270°	L-N	B	

4.1.5 Verdict

The EUT was working as normal, so they met the requirement of performance criteria B.

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4.2 ESD

4.2.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Series No.	Cal. Date	Cal. date	Due
1	Electrostatic Discharge Simulator	KIKUSUI	KES4021	LL004798	2017-12-25	2018-12-24	

4.2.2 Description of Measurement Conditions

Temperature: 21 °C
 Humidity: 58%
 Pressure: 1033mbar
 Electromagnetic environment: normal

4.2.3 Configuration

The configuration is in accordance with the requirement in EN61000-4-2, see the photo in appendix.

4.2.4 Test Data and Records

Air Discharge

Test Levels																
EN61000-4-2 Test Points	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-10 kV	+10 kV	-12.5 kV	+12.5 kV	-15 kV	+15 kV	-20 kV	+20 kV
EUT Front Side	B	B	B	B	B	B	B	B								
EUT Top Side	B	B	B	B	B	B	B	B								
EUT Back Side	B	B	B	B	B	B	B	B								
EUT Left Side	B	B	B	B	B	B	B	B								
EUT Right Side	B	B	B	B	B	B	B	B								

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Direct Contact

Test Levels																
EN61000-4-2 Test Points	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-10 kV	+10 kV	-12.5 kV	+12.5 kV	-15 kV	+15 kV	-20 kV	+20 kV
EUT Front Side	B	B	B	B												
EUT Top Side	B	B	B	B												
EUT Back Side	B	B	B	B												
EUT Left Side	B	B	B	B												
EUT Right Side	B	B	B	B												

4.2.5 Verdict

The EUT was working as normal, so they met the requirement of performance criteria B.

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4.3 EFT/B

4.3.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Series No.	Cal. Date	Cal. date	Due
1	Ultra-compact simulator	EM test	UCS500M4	V050710012 2	2017-09-04	2018-09-03	

4.3.2 Description of Measurement Conditions

Temperature: 21 °C
 Humidity: 58%
 Pressure: 1033mbar
 Electromagnetic environment: normal

4.3.3 Configuration

The configuration is in accordance with the requirement in EN61000-4-4, see the photo in appendix.

4.3.4 Test Data and Records

Test Levels (kV)									
EN61000-4-4 Test Points		+0.25	-0.25	+0.5	-0.5	+1.0	-1.0	+2.0	-2.0
Power Port of EUT	L	B	B	B	B	B	B		
	N	B	B	B	B	B	B		
	L+N	B	B	B	B	B	B		

4.3.5 Verdict

The EUT was working as normal, so they met the requirement of performance criteria B.

4.4 Radio-frequency continuous conducted, 0.15 MHz to 80 MHz

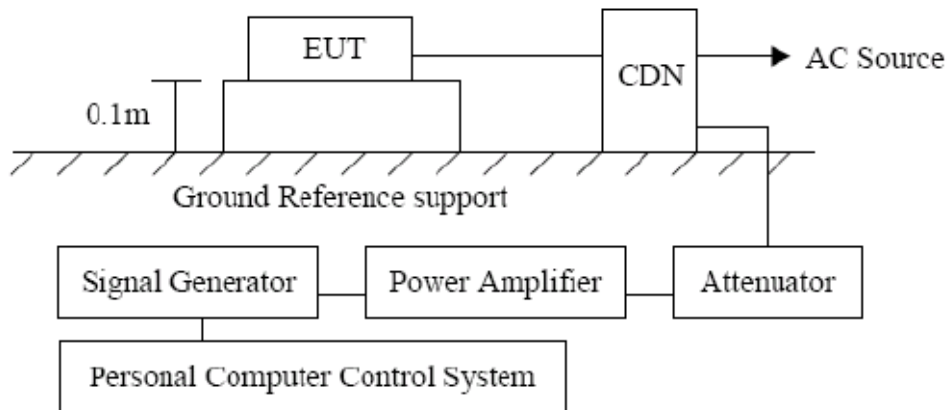
4.4.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Series No.	Cal. Date	Cal.Due date
1	AM/FM signal generator	AEROFLEX	2023A	202306/668	2017-10-21	2018-10-20
2	PAMP Conducted RF test system	HAEFFLY	PAMP250	151730	2017-10-21	2018-10-20
3	CDN impedance and K-factor	LUTHI	L-801 M2/M3	9931	/	/

4.4.2 Description of Measurement Conditions

Temperature: 22°C
 Humidity: 59%
 Pressure: 1033mbar
 Electromagnetic environment: normal

4.4.3 Configuration



4.4.4 Test Data and Records

EN61000-4-6 Test Points	Frequency range MHz	Levels	Voltage Level (e.m.f.)V	Pass	Fail
Power Line	0.15-80MHz	1	1		
		2	3	A	
		3	10		
		X	Special		

4.4.5 Verdict

The EUT was working as normal, so they met the requirement of performance criteria A.

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4.5 VOLTAGE DIPS AND INTERRUPTIONS

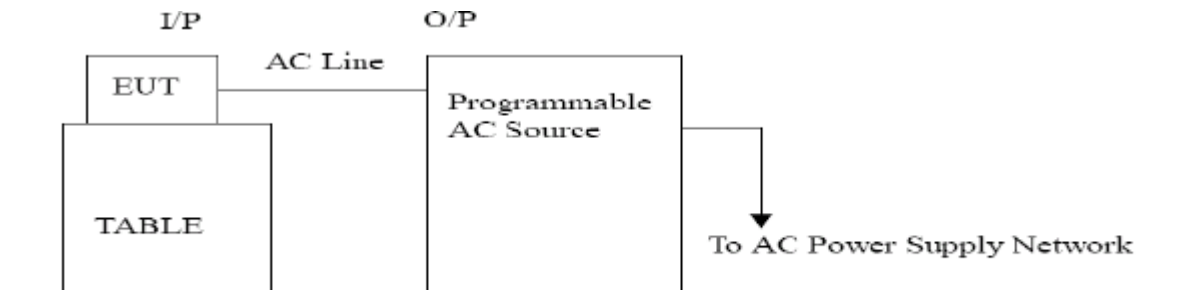
4.5.1 Test Equipment List and Details

Item	Test Equipment	Manufacturer	Model No.	Series No.	Cal. Date	Cal. Due date
1	Ultra-compact simulator	EM test	UCS500M4	V0507100789	2017-10-08	2018-10-07
2	Motorised Variac	EM test	MV2616	V0507100459	2017-10-08	2018-10-07

4.5.2 Description of Measurement Conditions

Temperature: 21 °C
 Humidity: 58%
 Pressure: 1033mbar
 Electromagnetic environment: normal

4.5.3 Configuration



4.5.4 Test Data and Records

Environmental phenomena		Test level in % U_T	Duration (in periods of the rated frequency)	Phase Angle	Pass	Fail
Interruptions	>95	<5	250T	0/180	C	
Voltage dips in % U_T	>95	<5	0.5T	0/180	B	

4.5.5 Verdict

The EUT was working as normal, so they met the requirement of performance criteria C.

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APPENDIX —PHOTOGRAPH



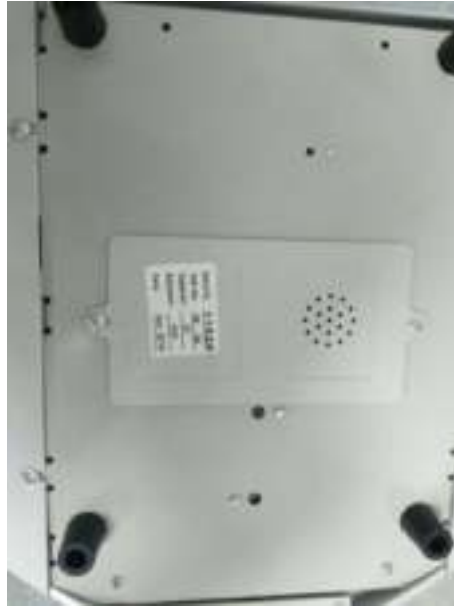
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